

RELIABILITY REPORT  
FOR  
MAX135CPI+  
PLASTIC ENCAPSULATED DEVICES

October 2, 2009

**MAXIM INTEGRATED PRODUCTS**

120 SAN GABRIEL DR.  
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## Conclusion

The MAX135CPI+ successfully meets the quality and reliability standards required of all Maxim products. In addition, Maxim's continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards.

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### I. Device Description

#### A. General

The MAX135 is a CMOS 15-bit, binary-output analog-to-digital converter (ADC). Multi-slope integration provides low-noise and high-resolution conversions in less time than standard integrating ADCs: The MAX135 is tested at 16 conversions per second, but operates at up to 6 times that rate. The MAX135 uses Super LSBs with data averaging to achieve 18-bit resolution. Supply current is 125 $\mu$ A maximum during normal operation and only 10 $\mu$ A maximum in sleep mode. Low conversion noise allows tested operation at only 300mV full scale (15 $\mu$ V per LSB). A simple 8-bit parallel data bus and three control lines easily interface to all common microprocessors, and twos-complement output coding simplifies bipolar measurements. High resolution and compact size make the MAX135 ideal for data loggers, numerical control systems, weight scales, data-acquisition systems, and panel meters. The MAX135 comes in 28-pin DIP and SO packages in both commercial and extended temperature grades.

## II. Manufacturing Information

A. Description/Function:	±15-Bit, Low-Power ADC with Parallel Interface
B. Process:	M6
C. Number of Device Transistors:	
D. Fabrication Location:	Oregon
E. Assembly Location:	Philippines, Thailand
F. Date of Initial Production:	Pre 1997

## III. Packaging Information

A. Package Type:	28-pin PDIP
B. Lead Frame:	Copper
C. Lead Finish:	100% matte Tin
D. Die Attach:	Conductive Epoxy
E. Bondwire:	Gold (1.3 mil dia.)
F. Mold Material:	Epoxy with silica filler
G. Assembly Diagram:	#05-0101-0275
H. Flammability Rating:	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard J-STD-020-C	Level 1
J. Single Layer Theta Ja:	70°C/W
K. Single Layer Theta Jc:	21°C/W

## IV. Die Information

A. Dimensions:	141 X 178 mils
B. Passivation:	Si <sub>3</sub> N <sub>4</sub> /SiO <sub>2</sub> (Silicon nitride/ Silicon dioxide)
C. Interconnect:	Al/1.0%Si
D. Backside Metallization:	None
E. Minimum Metal Width:	Metal1 = 0.5 / Metal2 = 0.6 / Metal3 = 0.6 microns (as drawn)
F. Minimum Metal Spacing:	Metal1 = 0.45 / Metal2 = 0.5 / Metal3 = 0.6 microns (as drawn)
G. Bondpad Dimensions:	5 mil. Sq.
H. Isolation Dielectric:	SiO <sub>2</sub>
I. Die Separation Method:	Wafer Saw

## V. Quality Assurance Information

A. Quality Assurance Contacts:	Ken Wendel (Director, Reliability Engineering) Bryan Preeshl (Managing Director of QA)
B. Outgoing Inspection Level:	0.1% for all electrical parameters guaranteed by the Datasheet. 0.1% For all Visual Defects.
C. Observed Outgoing Defect Rate:	< 50 ppm
D. Sampling Plan:	Mil-Std-105D

## VI. Reliability Evaluation

### A. Accelerated Life Test

The results of the 135°C biased (static) life test are shown in Table 1. Using these results, the Failure Rate ( $\lambda$ ) is calculated as follows:

$$\lambda = \frac{1}{\text{MTTF}} = \frac{4.05}{192 \times 4340 \times 80 \times 2} \quad (\text{Chi square value for MTTF upper limit})$$

(where 4340 = Temperature Acceleration factor assuming an activation energy of 0.8eV)

$$\lambda = 29.6 \times 10^{-9}$$

$$\lambda = 29.6 \text{ F.I.T. (60\% confidence level @ 25°C)}$$

The following failure rate represents data collected from Maxim's reliability monitor program. Maxim performs quarterly life test monitors on its processes. This data is published in the Reliability Report found at <http://www.maxim-ic.com/qa/reliability/monitor>. Cumulative monitor data for the M6 Process results in a FIT Rate of 0.22 @ 25C and 3.73 @ 55C (0.8 eV, 60% UCL)

### B. Moisture Resistance Tests

The industry standard 85°C/85%RH or HAST testing is monitored per device process once a quarter.

### C. E.S.D. and Latch-Up Testing

The AD57 die type has been found to have all pins able to withstand a HBM transient pulse of +/-400 V per Mil-Std 883 Method 3015.7. Latch-Up testing has shown that this device withstands a current of +/-100 mA.

**Table 1**  
Reliability Evaluation Test Results

**MAX135CPI+**

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	SAMPLE SIZE	NUMBER OF FAILURES
<b>Static Life Test</b> (Note 1)				
	Ta = 135°C Biased Time = 192 hrs.	DC Parameters & functionality	80	1
<b>Moisture Testing</b> (Note 2)				
HAST	Ta = 130°C RH = 85% Biased Time = 96hrs.	DC Parameters & functionality	77	0
<b>Mechanical Stress</b> (Note 2)				
Temperature Cycle	-65°C/150°C 1000 Cycles Method 1010	DC Parameters & functionality	77	0

Note 1: Life Test Data may represent plastic DIP qualification lots.

Note 2: Generic Package/Process data